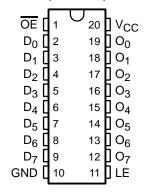
- Function and Pinout Compatible With FCT and F Logic
- Reduced V<sub>OH</sub> (Typically = 3.3 V) Versions of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- 3-State Outputs
- CY54FCT573T
  - 32-mA Output Sink Current
  - 12-mA Output Source Current
- CY74FCT573T
  - 64-mA Output Sink Current
  - 32-mA Output Source Current

#### CY54FCT573T . . . D PACKAGE CY74FCT573T . . . P, Q, OR SO PACKAGE (TOP VIEW)



### description

The 'FCT573T devices consist of eight latches with 3-state outputs for bus-organized applications. When the latch-enable (LE) input is high, the flip-flops appear transparent to the data. Data that meets the required setup times are latched when LE transitions from high to low. Data appears on the bus when the output-enable  $(\overline{OE})$  input is low. When  $\overline{OE}$  is high, the bus output is in the high-impedance state. In this mode, data can be entered into the latches. The 'FCT573T devices are identical to the 'FCT373T devices, except for the flow-through pinout of the 'FCT573T, which simplifies board design.

These devices are fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



### **ORDERING INFORMATION**

TA	PACKAGE†		SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING	
	QSOP – Q	Tape and reel	4.7	CY74FCT573CTQCT	FCT573C	
	SOIC - SO	Tube	4.7	CY74FCT573CTSOC	FCT573C	
	3010 - 30	Tape and reel	4.7	CY74FCT573CTSOCT	FC1573C	
	DIP – P	Tube	5.2	CY74FCT573ATPC	CY74FCT573ATPC	
-40°C to 85°C	QSOP – Q	Tape and reel	5.2	CY74FCT573ATQCT	FCT573A	
-40 C to 65 C	SOIC - SO	Tube	5.2	CY74FCT573ATSOC	FCT573A	
	3010 - 30	Tape and reel	5.2	CY74FCT573ATSOCT	FC1575A	
	QSOP – Q	Tape and reel	8	CY74FCT573TQCT	FCT573	
	SOIC - SO	Tube	8	CY74FCT573TSOC	FCT573	
	3010 - 30	Tape and reel	8	CY74FCT573TSOCT	FC13/3	
–55°C to 125°C	CDIP – D	Tube	8.5	CY54FCT573ATLMB		

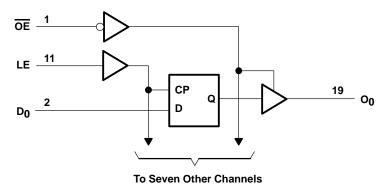
<sup>†</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

#### **FUNCTION TABLE**

	INPUTS		OUTPUT
OE	LE	D	0
L	Н	Н	Н
L	Н	L	L
L	L	Χ	$Q_0$
Н	X	X	Z

H = High logic level, L = Low logic level, X = Don't care, Z = High-impedance state,  $Q_n$  = Previous state of flip flops ( $Q_{n-1}$ )

# logic diagram (positive logic)



### absolute maximum rating over operating free-air temperature range (unless otherwise noted)†

Supply voltage range to ground potential	–0.5 V to 7 V
DC input voltage range	0.5 V to 7 V
DC output voltage range	0.5 V to 7 V
DC output current (maximum sink current/pin)	120 mA
Package thermal impedance, $\theta_{JA}$ (see Note 1): P package	age 69°C/W
Q pack	age 68°C/W
SO pac	kage 58°C/W
Ambient temperature range with power applied, T <sub>A</sub>	–65°C to 135°C
Storage temperature range, T <sub>sta</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions (see Note 2)

		CY	54FCT57	'3T	CY74FCT573T		UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ІОН	High-level output current			-12			-32	mA
loL	Low-level output current			32			64	mA
T <sub>A</sub>	Operating free-air temperature	-55		125	-40		85	°C

NOTE 2: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation.



NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.

# CY54FCT573T, CY74FCT573T 8-BIT LATCHES WITH 3-STATE OUTPUTS

SCCS068 - OCTOBER 2001

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST CONDITIONS			54FCT57	73T	CY	74FCT57	73T	
PARAMETER		TEST CONDITIO	ONS	MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
V/	$V_{CC} = 4.5 \text{ V},$	I <sub>IN</sub> = -18 mA			-0.7	-1.2				V
VIK	$V_{CC} = 4.75 \text{ V},$	I <sub>IN</sub> = -18 mA						-0.7	-1.2	v
	$V_{CC} = 4.5 \text{ V},$	I <sub>OH</sub> = -12 mA		2.4	3.3					
Vон	V <sub>CC</sub> = 4.75 V	$I_{OH} = -32 \text{ mA}$					2			V
	VCC = 4.75 V	$I_{OH} = -15 \text{ mA}$					2.4	3.3		
Va	$V_{CC} = 4.5 \text{ V},$	I <sub>OL</sub> = 32 mA			0.3	0.55				V
VOL	$V_{CC} = 4.75 \text{ V},$	I <sub>OL</sub> = 64 mA						0.3	0.55	V
$V_{hys}$	All inputs				0.2			0.2		V
	V <sub>CC</sub> = 5.5 V,	VIN = VCC				5				4
t <sub>l</sub>	V <sub>CC</sub> = 5.25 V,	VIN = VCC							5	μΑ
	$V_{CC} = 5.5 \text{ V},$	V <sub>IN</sub> = 2.7 V				±1				^
lΗ	V <sub>CC</sub> = 5.25 V,	V <sub>IN</sub> = 2.7 V							±1	μΑ
1	V <sub>CC</sub> = 5.5 V,	V <sub>IN</sub> = 0.5 V			-	±1			±1 ±1	
Iμ	V <sub>CC</sub> = 5.25 V,	V <sub>IN</sub> = 0.5 V			-				±1	μΑ
	V <sub>CC</sub> = 5.5 V,	V <sub>OUT</sub> = 2.7 V				10				4
IOZH	V <sub>CC</sub> = 5.25 V,	V <sub>OUT</sub> = 2.7 V							10	μΑ
1	$V_{CC} = 5.5 \text{ V},$	V <sub>OUT</sub> = 0.5 V				-10				
IOZL	$V_{CC} = 5.25 \text{ V},$	V <sub>OUT</sub> = 0.5 V							-10	μΑ
ı <del>†</del>	$V_{CC} = 5.5 \text{ V},$	V <sub>OUT</sub> = 0 V		-60	-120	-225				A
IOS <sup>‡</sup>	$V_{CC} = 5.25 \text{ V},$	V <sub>OUT</sub> = 0 V					-60	-120	-225	mA
I <sub>off</sub>	$V_{CC} = 0 V$ ,	V <sub>OUT</sub> = 4.5 V				±1			±1	μΑ
	V <sub>CC</sub> = 5.5 V,	V <sub>IN</sub> ≤ 0.2 V,	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.1	0.2				A
ICC	V <sub>CC</sub> = 5.25 V,	V <sub>IN</sub> ≤ 0.2 V,	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$					0.1	0.2	mA
41	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub>	$_{\text{V}} = 3.4 \text{ V}$ , $f_1 = 0$ , O	utputs open		0.5	2				A
∇ICC	V <sub>CC</sub> = 5.25 V, V	$I_{IN} = 3.4 \text{ V}$ , $f_1 = 0$ ,	Outputs open					0.5	2	mA
	V <sub>CC</sub> = 5.5 V, Ou One input switch	itputs open, ning at 50% duty cyc	$\overline{\text{OE}} = \text{GND},$		0.06	0.12				
10.5-¶		$IN \ge V_{CC} - 0.2 \text{ V}$	· ,	<u> </u>						mA/
ICCD¶		outputs open, ning at 50% duty cyc IN ≥ VCC - 0.2 V	le, <del>OE</del> = GND,					0.06	0.12	MHz

<sup>†</sup> Typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

 $<sup>\</sup>$  Per TTL-driven input ( $V_{IN} = 3.4 \text{ V}$ ); all other inputs at  $V_{CC}$  or GND

<sup>¶</sup> This parameter is derived for use in total power-supply calculations.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

DADAMETER		TEST CONDITION	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	UNIT						
PARAMETER	TEST CONDITIONS			MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
	V <sub>CC</sub> = 5.5 V,	One bit switching at f <sub>1</sub> = 10 MHz			0.7	1.4				
	Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1	2.4				
	OE = GND, LE = V <sub>CC</sub>	Eight bits switching at f <sub>1</sub> = 2.5 MHz			1.3	2.6				
1-#		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		3.3	10.6				mA
I IC"	V <sub>CC</sub> = 5.25 V,	One bit switching at f <sub>1</sub> = 10 MHz						0.7		IIIA
	Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					1	2.4	
	OE = GND, LE = V <sub>CC</sub>	Eight bits switching at f <sub>1</sub> = 2.5 MHz						1.3	1.7 1.4 1 2.4 .3 2.6	
		at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$					3.3		
C <sub>i</sub>					6	10		6	10	pF
Co					8	12		8	12	pF

<sup>&</sup>lt;sup>†</sup> Typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

Where:

IC = Total supply current

I<sub>CC</sub> = Power-supply current with CMOS input levels

 $\Delta I_{CC}$  = Power-supply current for a TTL high input (V<sub>IN</sub> = 3.4 V)

 $D_H$  = Duty cycle for TTL inputs high  $N_T$  = Number of TTL inputs at  $D_H$ 

ICCD = Dynamic current caused by an input transition pair (HLH or LHL)

= Clock frequency for registered devices, otherwise zero

f<sub>1</sub> = Input signal frequency

N<sub>1</sub> = Number of inputs changing at f<sub>1</sub>

All currents are in milliamperes and all frequencies are in megahertz.

Values for these conditions are examples of the ICC formula.

# timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY54FC	T573T	CY54FCT	573AT	UNIT
		MIN	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, LE high	6		6		ns
t <sub>su</sub>	Setup time, data before LE↑	2		2		ns
th	Hold time, data after LE↑	1.5		1.5		ns

# timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

		CY74FC	T573T	CY74FCT	573AT	CY74FCT	573CT	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>W</sub>	Pulse duration, LE high	6		5		5		ns
t <sub>su</sub>	Setup time, data before LE↑	2		2		2		ns
th	Hold time, data after LE↑	1.5		1.5		1.5		ns



 $<sup>^{\#}</sup>$ IC = ICC +  $\triangle$ ICC  $\times$  DH  $\times$  NT + ICCD (f<sub>0</sub>/2 + f<sub>1</sub>  $\times$  N<sub>1</sub>)

# **CY54FCT573T, CY74FCT573T** 8-BIT LATCHÉS WITH 3-STATE OUTPUTS SCCS068 - OCTOBER 2001

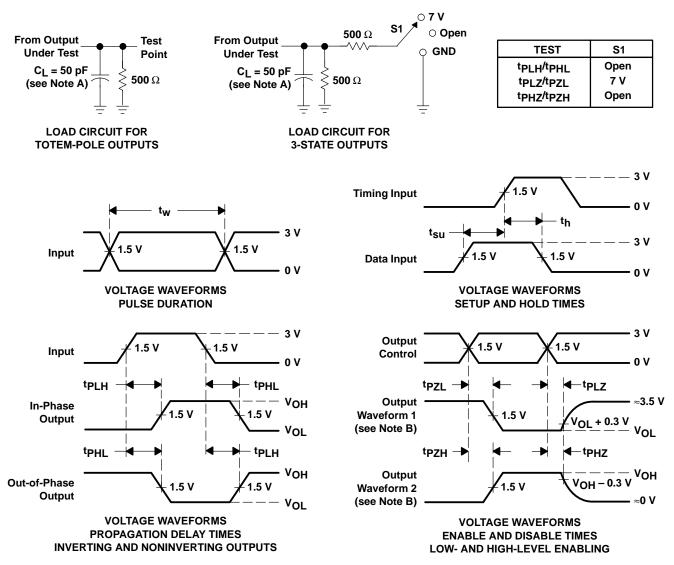
# switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	CY54FCT	573AT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	UNIT
<sup>t</sup> PLH	D	0	1.5	5.6	nc
<sup>t</sup> PHL	ט	O	1.5	5.6	ns
<sup>t</sup> PLH	LE	0	2	9.8	ns
<sup>t</sup> PHL	LL		2	9.8	115
<sup>t</sup> PZH	ŌĒ	0	1.5	7.5	ns
t <sub>PZL</sub>	OE .	O	1.5	7.5	115
<sup>t</sup> PHZ	ŌĒ	0	1.5	6.5	ns
t <sub>PLZ</sub>	OE .	J	1.5	6.5	115

# switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	CY74FC	T573T	CY74FCT	573AT	CY74FC1	573CT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
<sup>t</sup> PLH	D	0	1.5	8	1.5	5.2	1.5	4.7	ns
<sup>t</sup> PHL	U		1.5	8	1.5	5.2	1.5	4.7	110
<sup>t</sup> PLH	LE	0	2	13	2	8.5	2	5.5	200
<sup>t</sup> PHL	LC	O	2	13	2	8.5	2	5.5	ns
<sup>t</sup> PZH	ŌĒ	0	1.5	12	1.5	6.5	1.5	5.5	
<sup>t</sup> PZL	OE	U	1.5	12	1.5	6.5	1.5	5.5	ns
<sup>t</sup> PHZ	ŌĒ	0	1.5	7.5	1.5	5.5	1.5	5	200
<sup>t</sup> PLZ	J OE		1.5	7.5	1.5	5.5	1.5	5	ns

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

#### **IMPORTANT NOTICE**

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third—party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Mailing Address:

Texas Instruments Post Office Box 655303 Dallas, Texas 75265